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(71)(72) Applicant and Inventor: KLEY, Victor, B. [US/US]; 1119 Park Hill Road, Berkeley, CA 94708 (US).

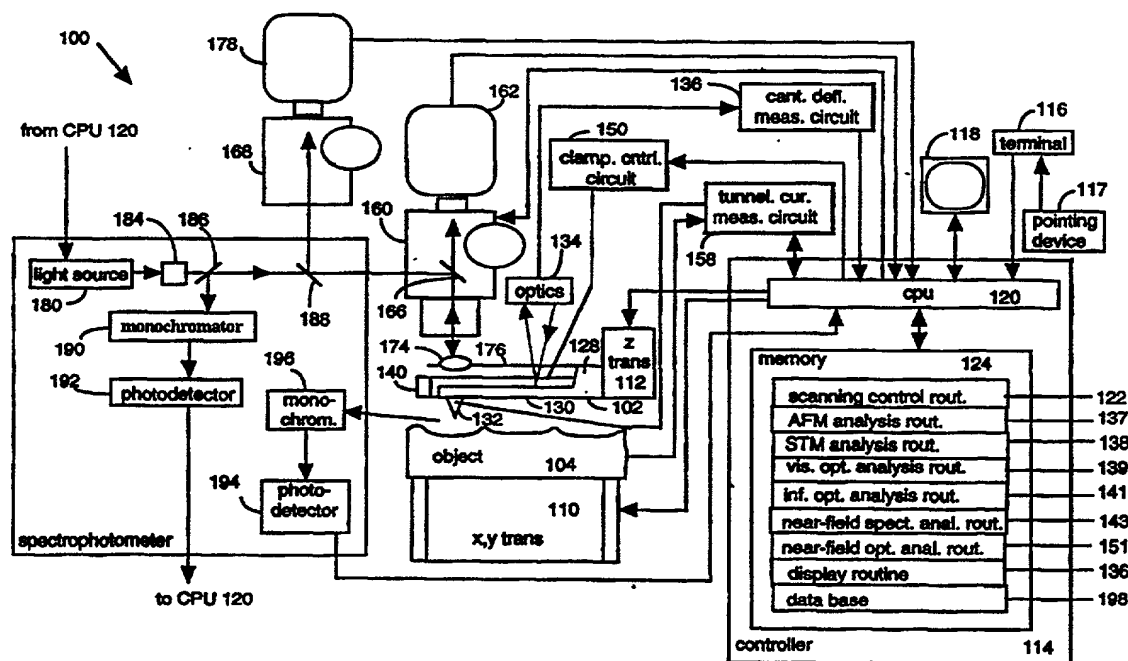
(74) Agents: TEST, Aldo, J. et al.; Flehr, Hohbach, Test, Albritton & Herbert, 4 Embarcadero Center, Suite 3400, San Francisco, CA 94111-4187 (US).

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(54) Title: SCANNING PROBE MICROSCOPE ASSEMBLY



(57) Abstract

A scanning probe microscope assembly (100) is disclosed that has an atomic force measurement (AFM) mode (137), a scanning tunneling measurement (STM) mode (138), a near-field spectrometry mode (143), a near-field optical mode (151), and a hardness testing mode for examining an object (104).